

# Search Notes



Application/Control No.

10/005,627

Examiner

Tse Chen

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

2116

## SEARCHED

Class	Subclass	Date	Examiner
713	320	10/5/05	TSE

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
713	300	10/11/05	TSE
713	320	10/11/05	TSE

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
7/3/320 LIMITED TXT - SEE SEARCH RPT PRTOU	9/25/05	TSE